

# Weighting observations from multi-station coordinate measuring systems

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MathMet 2010, 20–21 June, PTB Berlin

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## Overview

Multi-station coordinate measuring systems

Posterior distribution for noise parameters

Maximising the posterior distribution

Application to laser tracker calibration

## Large scale coordinate metrology

Target located at  $\mathbf{x}$ , station located at  $\mathbf{p}$ , orientation defined by rotation matrix  $R(\boldsymbol{\alpha})$ .

Distance to target given by  $\|\mathbf{x} - \mathbf{p}\|$ .

Azimuth and elevation angles: if  $\mathbf{n} = \|\mathbf{x} - \mathbf{p}\|/d^*$  then there are  $\theta^* = \theta^*(\mathbf{x}, \mathbf{p}, \boldsymbol{\alpha})$  and  $\phi^* = \phi^*(\mathbf{x}, \mathbf{p}, \boldsymbol{\alpha})$  such that

$$\begin{bmatrix} \cos \theta^* \cos \phi^* \\ \sin \theta^* \cos \phi^* \\ \sin \phi^* \end{bmatrix} = R(\boldsymbol{\alpha})\mathbf{n}.$$

Observations

$$d = d^* + \epsilon_D, \quad d^* = (1 + \mu)\|\mathbf{x} - \mathbf{p}\| + \lambda, \quad \theta = \theta^* + \epsilon_A, \quad \phi = \phi^* + \epsilon_E,$$

involving random effects

$$\epsilon_D \in N(0, \sigma_D^2), \quad \epsilon_A \in N(0, \sigma_A^2), \quad \epsilon_E \in N(0, \sigma_E^2),$$

due to refractive index changes, etc.

## Multi-station systems

Target parameters  $\mathbf{x}_j$ , coordinates of the location of the  $j$ th target

Configuration parameters  $\mathbf{b}$ : locations  $\mathbf{p}_k$ , orientation angles  $\alpha_k$  associated with the measuring stations, other systematic effects  $\lambda_l, \mu_r$ , etc.

Nonlinear least squares problem (MLE):

$$\min_{\{\mathbf{x}_j\}, \mathbf{b}} \sum_i \{w_{i,D}^2 (d_i - d_i^*(\mathbf{x}, \mathbf{b}))^2 + w_{i,A}^2 (\theta_i - \theta_i^*(\mathbf{x}, \mathbf{b}))^2 + w_{i,E}^2 (\phi_i - \phi_i^*(\mathbf{x}, \mathbf{b}))^2\}.$$

Weights  $w_{i,D} = 1/\sigma_{i,D}$ , etc.

Need to weight angle measurements relative to distance measurements.

## Adjusting noise parameters: single sensor case

Suppose

$$\mathbf{y}|\boldsymbol{\alpha} \sim \mathcal{N}(C\boldsymbol{\alpha}, \sigma^2 I), \quad C, \quad m \times n, \quad y_i = \alpha_1 + \alpha_2 x_i + \epsilon_i, \quad \epsilon_i \in \mathcal{N}(0, \sigma^2).$$

Least squares solution:

$$\mathbf{a} = (C^T C)^{-1} C^T \mathbf{y} = R_1^{-1} Q_1^T \mathbf{y}, \quad C = QR = [Q_1 \quad Q_2] \begin{bmatrix} R_1 \\ \mathbf{0} \end{bmatrix}.$$

Also

$$\hat{\mathbf{y}} = C\mathbf{a} = Q_1 Q_1^T \mathbf{y}, \quad \mathbf{r} = \mathbf{y} - \hat{\mathbf{y}} = (I - Q_1 Q_1^T) \mathbf{y} = Q_2 Q_2^T \mathbf{y},$$

so that

$$\mathbf{a}|\boldsymbol{\alpha}, \sigma \sim \mathcal{N}(\boldsymbol{\alpha}, \sigma^2 (C^T C)^{-1}), \quad \mathbf{r}|\boldsymbol{\alpha}, \sigma \sim \mathcal{N}(\mathbf{0}, \sigma^2 Q_2 Q_2^T).$$

If  $\tilde{\mathbf{r}} = Q_2^T \mathbf{r}$ ,

$$\tilde{\mathbf{r}}|\boldsymbol{\alpha}, \sigma \sim \mathcal{N}(\mathbf{0}, \sigma^2 I_{m-n}), \quad \frac{1}{\sigma^2} \mathbf{r}^T \mathbf{r} = \frac{1}{\sigma^2} \tilde{\mathbf{r}}^T \tilde{\mathbf{r}} \sim \chi_{m-n}^2.$$

Choose  $\hat{\sigma}$  such the observed  $\mathbf{r}^T \mathbf{r}$  is  $E(\mathbf{r}^T \mathbf{r}|\hat{\sigma})$ :

$$\hat{\sigma}^2 = \frac{\mathbf{r}^T \mathbf{r}}{m-n}, \quad E(\hat{\sigma}|\sigma) = \sigma.$$

## Partial information about $\sigma$

Classical estimation caters for  $\sigma$  known or completely unknown. Suppose there is partial information about  $\sigma$ , e.g., from a previous experiment.

Suitable prior distribution for  $\phi = 1/\sigma^2$ :

$$m_0\sigma_0^2\phi \sim \chi_{m_0}^2, \quad p(\phi) \propto \phi^{m_0/2-1} \exp\left\{-\frac{\phi}{2}m_0\sigma_0^2\right\},$$

where  $\sigma_0$  is the prior estimate and  $m_0$  encodes degree of belief in  $\sigma_0$ . This prior corresponds to information gained about  $\sigma$  by observing a standard deviation of  $\sigma_0$  of  $m_0$  samples  $z_i \in N(0, \sigma^2)$ .

Applying Bayes' theorem

$$p(\boldsymbol{\alpha}, \sigma | \mathbf{y}) \propto \phi^{(m_0+m)/2-1} \exp\left\{-\frac{\phi}{2} [m_0\sigma_0^2 + ms^2 + (\boldsymbol{\alpha} - \mathbf{a})^\top C^\top C (\boldsymbol{\alpha} - \mathbf{a})]\right\},$$

where

$$\mathbf{a} = (C^\top C)^{-1} C^\top \mathbf{y}, \quad \mathbf{r} = \mathbf{y} - C\mathbf{a}, \quad ms^2 = \mathbf{r}^\top \mathbf{r}.$$

## Marginal distributions

Model parameters:

$$p(\boldsymbol{\alpha}|\mathbf{y}) = \int_S p(\boldsymbol{\alpha}, \sigma|\mathbf{y})d\sigma \Rightarrow \boldsymbol{\alpha} \sim t_\nu(\mathbf{a}, \bar{\mathbf{V}}),$$

where

$$\nu = m_0 + m - n, \quad \bar{\mathbf{V}} = \bar{\sigma}^2(\mathbf{C}^\top \mathbf{C})^{-1}, \quad \bar{\sigma}^2 = \frac{m_0\sigma_0^2 + m s^2}{m_0 + m - n}.$$

If  $m_0 \mapsto \infty$ ,  $\bar{\sigma}^2 \mapsto \sigma_0^2$ , if  $m_0 \mapsto 0$ ,  $\bar{\sigma}^2 \mapsto \hat{\sigma}^2$ .

Noise parameter:

$$p(\sigma|\mathbf{y}) = \int_A p(\boldsymbol{\alpha}, \sigma|\mathbf{y})d\boldsymbol{\alpha} \Rightarrow \nu\bar{\sigma}^2\phi \sim \chi_\nu^2.$$

## Multiple sensors

Suppose

$$\mathbf{y}_k | \boldsymbol{\alpha}, \sigma_k \sim \mathcal{N}(C_k \boldsymbol{\alpha}, \sigma_k^2 I), \quad k = 1, \dots, n_K,$$

where  $C_k$  is  $m_k \times n$ . Let

$$V_{\boldsymbol{\sigma}} = \begin{bmatrix} \sigma_1^2 I_{m_1} & & \\ & \dots & \\ & & \sigma_{n_K}^2 I_{m_{n_K}} \end{bmatrix}, \quad C = \begin{bmatrix} C_1 \\ \vdots \\ C_{n_K} \end{bmatrix}, \quad \mathbf{y} = \begin{bmatrix} \mathbf{y}_1 \\ \vdots \\ \mathbf{y}_{n_K} \end{bmatrix}, \quad m = \sum_{k=1}^{n_K} m_k.$$

Naive posterior estimate of  $\sigma_k$  if  $m_k > n$ : given estimates  $\sigma_{0,k}$ , determine the least squares solution  $\mathbf{a}$  of

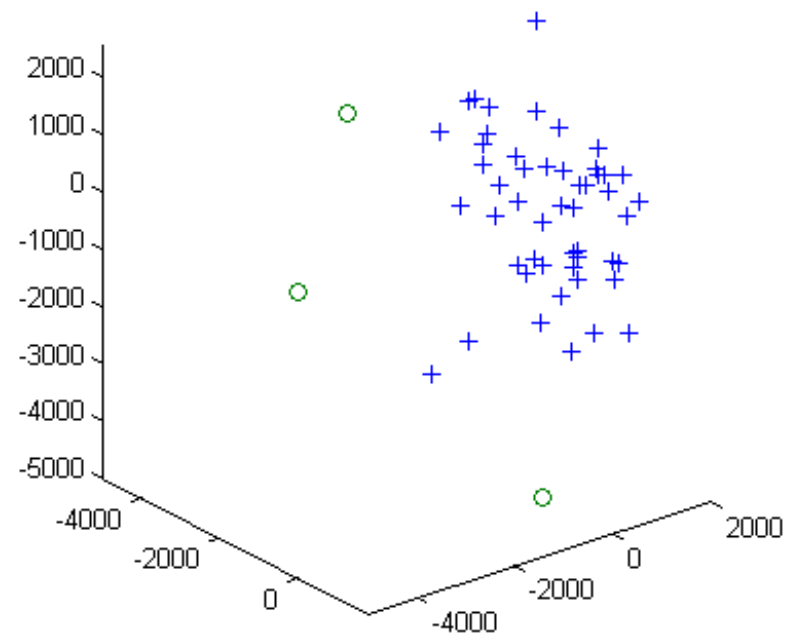
$$\min_{\boldsymbol{\alpha}} (\mathbf{y} - C\boldsymbol{\alpha})^\top V_{\boldsymbol{\sigma}}^{-1} (\mathbf{y} - C\boldsymbol{\alpha}),$$

and set

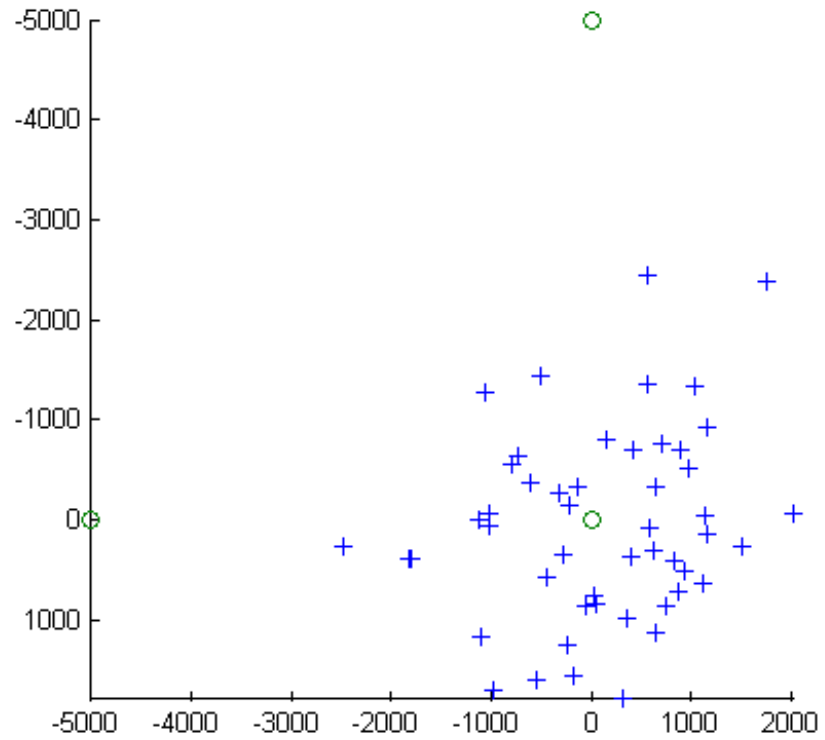
$$\mathbf{r}_k = \mathbf{y}_k - C\mathbf{a}, \quad \hat{\sigma}_k^2 = \frac{m_k}{m} \frac{\mathbf{r}_k^\top \mathbf{r}_k}{m - n}.$$



## Example: three laser trackers



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$$\hat{\sigma}_k^2 = \frac{m_k \mathbf{r}_k^\top \mathbf{r}_k}{m \ m - n}$$

$$\hat{\sigma}_D = 0.39, \quad \hat{\sigma}_A = \hat{\sigma}_E = 1.17.$$

Use these estimates to reweight, and recalculate  $\hat{\sigma}_k$ :

$$\hat{\sigma}_D = 0.13, \quad \hat{\sigma}_A = \hat{\sigma}_E = 1.05.$$

Better to compare  $\mathbf{r}$  with  $u(\mathbf{r})$  derived from  $\mathbf{r}|\alpha, \sigma \sim N(\mathbf{0}, \sigma^2 Q_2 Q_2^\top)$ , to take into account leverage (but ignoring correlation).

(ILCs:  $C = (5, 1, 1, 1, 1, 1, 1, 1)^\top$ ,  $u(\mathbf{r}) = (0.26, 1, 1, 1, 1, 1, 1, 1)^\top$ . [Remember,  $\mathbf{r}$  is the *weighted* residual.]

## Multiple sensors, Bayesian approach

Prior information about  $\phi_k = 1/\sigma_k^2$  given by

$$m_{0,k}\sigma_{0,k}^2\phi_k \sim \chi_{m_{0,k}}^2.$$

Assuming prior independence of  $p(\phi_k)$ ,

$$p(\phi) \propto \left( \prod_{k=1}^{n_K} \phi_k^{n_{0,k}/2-1} \right) \exp \left\{ -\frac{1}{2} \sum_{k=1}^{n_K} n_{0,k}\sigma_{0,k}^2\phi_k \right\}.$$

Let

$$V_\phi = \begin{bmatrix} \phi_1^{-1} I_{m_1} & & \\ & \dots & \\ & & \phi_{n_K}^{-1} I_{m_{n_K}} \end{bmatrix}, \quad C = \begin{bmatrix} C_1 \\ \vdots \\ C_{n_K} \end{bmatrix}, \quad \mathbf{y} = \begin{bmatrix} \mathbf{y}_1 \\ \vdots \\ \mathbf{y}_{n_K} \end{bmatrix}, \quad m = \sum_{k=1}^{n_K} m_k.$$

If  $p(\alpha) \propto 1$ , then the posterior distribution for  $\alpha$  and  $\phi$  is such that

$$p(\alpha, \phi | \mathbf{y}) \propto p(\phi) |V_\phi|^{-1/2} \exp \left\{ -\frac{1}{2} (\mathbf{y} - C\alpha)^\top V_\phi^{-1} (\mathbf{y} - C\alpha) \right\}.$$

## Marginalised distribution

The marginalised distribution  $p(\phi|\mathbf{y})$  is given by

$$p(\phi|\mathbf{y}) = \int p(\boldsymbol{\alpha}, \phi|\mathbf{y}) d\boldsymbol{\alpha}.$$

Let  $\mathbf{a} = \mathbf{a}(\phi)$  solve

$$\min_{\boldsymbol{\alpha}} (\mathbf{y} - C\boldsymbol{\alpha})^T V_{\phi}^{-1} (\mathbf{y} - C\boldsymbol{\alpha})$$

and set

$$(ms^2 = \mathbf{r}^T \mathbf{r} =) \quad F(\phi) = (\mathbf{y} - C\mathbf{a}) V_{\phi}^{-1} (\mathbf{y} - C\mathbf{a}).$$

Then

$$p(\phi|\mathbf{y}) \propto p(\phi) |V_{\phi}|^{-1/2} |C^T V_{\phi}^{-1} C|^{-1/2} \exp \left\{ -\frac{1}{2} F(\phi) \right\}.$$

The  $\phi$  that maximises  $p(\phi|\mathbf{y})$  can be found by minimising  $-\log p(\phi|\mathbf{y})$  or equivalently, minimising

$$E(\phi|\mathbf{y}) = \frac{1}{2} \left( F(\phi) + \log |V_{\phi}| + \log |C^T V_{\phi}^{-1} C| \right) - \log p(\phi).$$

**Evaluating**  $E(\phi|y) = \frac{1}{2} \left( F(\phi) + \log |V_\phi| + \log |C^\top V_\phi^{-1} C| \right) - \log p(\phi)$

Firstly,

$$\log |V_\phi| = - \sum_{k=1}^{n_k} m_k \log \phi_k.$$

Let

$$V_\phi^{-1} = W_\phi^2, \quad C_\phi = W_\phi C, \quad y_\phi = W_\phi y.$$

If  $C_\phi$  has QR factorisation

$$C_\phi = [Q_1 \ Q_2] \begin{bmatrix} R_1 \\ \mathbf{0} \end{bmatrix} = Q_1 R_1,$$

then

$$\log |C^\top V_\phi^{-1} C| = \sum_{i=1}^n \log r_{ii}^2$$

where  $r_{ii}$  is the  $i$ th diagonal element of  $R_1$ , and

$$F(\phi) = \mathbf{q}_2^\top \mathbf{q}_2, \quad \mathbf{q}_2 = Q_2^\top y.$$

## Evaluating $\partial E(\phi|\mathbf{y})/\partial\phi_k$

Matrix determinant lemma: if  $A$  is square, full rank and a function of  $\phi$ , then

$$\frac{d}{d\phi} \log |A| = \text{Tr} \left[ A^{-1} \frac{dA}{d\phi} \right].$$

Let

$$W_k = \frac{\partial W_\phi}{\partial \phi_k} = \text{diag}(\mathbf{0}, \mathbf{1}_k, \mathbf{0})^\top.$$

We have

$$\frac{\partial}{\partial \phi_k} \log |V_\phi| = -\frac{m_k}{\phi_k},$$

$$\frac{\partial}{\partial \phi_k} \log |C^\top V_\phi^{-1} C| = 2\text{Tr}(S_k), \quad R_1 S_k = Q_1^\top W_k C$$

## Derivative calculations for least squares with matrices of functions

Let  $m \times n$  matrix  $C = C(\phi)$  be a function of a parameter  $\phi$  and let  $\dot{C} = dC/d\phi$  and

$$C = [Q_1 \ Q_2] \begin{bmatrix} R_1 \\ \mathbf{0} \end{bmatrix}, \quad \mathbf{a} = (C^T C)^{-1} C^T \mathbf{y} \quad \mathbf{r} = \mathbf{y} - C\mathbf{a}.$$

Then

$$\frac{d}{d\phi} [C(C^T C)^{-1} C^T] = F + F^T, \quad F = Q_2 Q_2^T \dot{C} R_1^{-1} Q_1^T,$$

and

$$\frac{d}{d\phi} \mathbf{a} = (F + F^T) \mathbf{y}, \quad \frac{d}{d\phi} \mathbf{r}^T \mathbf{r} = -2\mathbf{r}^T \dot{C} \mathbf{a}.$$

If  $\mathbf{y}$  is also a function of  $\phi$ , then

$$\frac{d}{d\phi} \mathbf{r}^T \mathbf{r} = 2\mathbf{r}^T (\dot{\mathbf{y}} - \dot{C} \mathbf{a}).$$



## Application to $F(\phi)$

$$\frac{\partial F}{\partial \phi_k}(\phi) = 2(\mathbf{y}_\phi - C_\phi \mathbf{a})^\top W_k (\mathbf{y} - C \mathbf{a}) = 2\mathbf{q}_2^\top W_k W_\phi^{-1} (Q_2 \mathbf{q}_2).$$

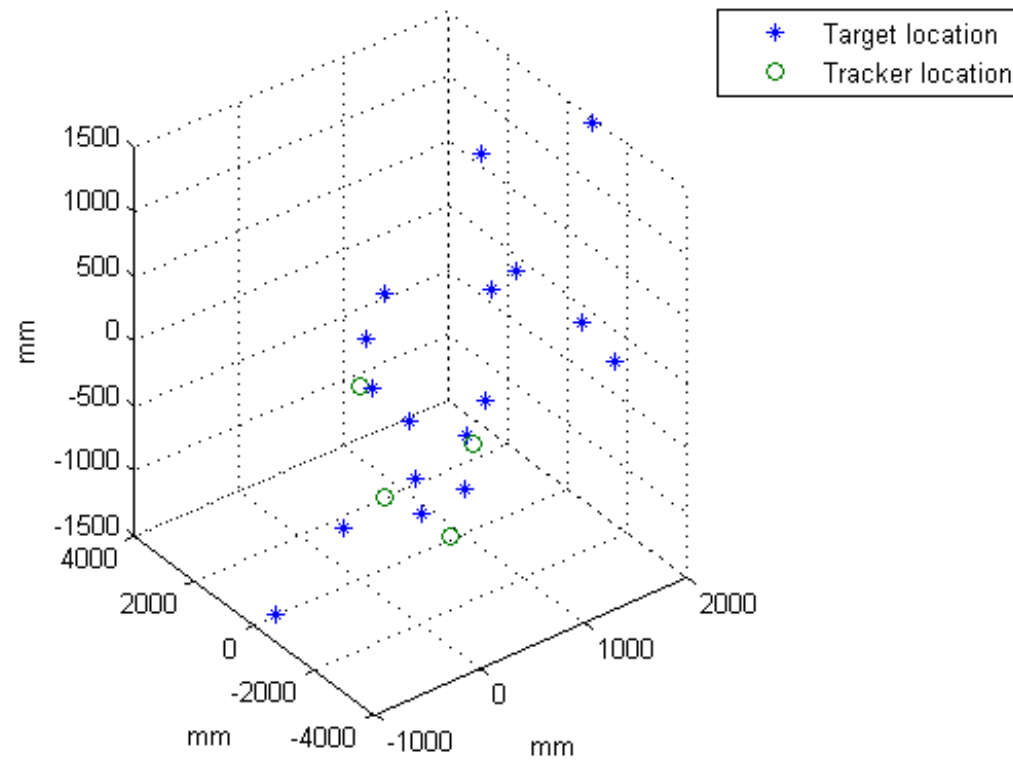
## Partial upper-triangularisation

Let  $Q_k$  be such that

$$Q_k^\top \begin{bmatrix} C_k & \mathbf{y}_k \end{bmatrix} = \begin{bmatrix} R_k & \mathbf{q}_k \\ & q_{0,k} \end{bmatrix}.$$

Then the least squares problem defined by  $\{C_k, \mathbf{y}_k\}$  is equivalent to that defined by  $\{R_k, \mathbf{q}_k, q_{0,k}\}$ .

## Tracker calibration experiments



## Results

	sigma_0	sigma(Bayes)
distance	5.00e-3 mm	2.86e-3 mm
angle	5.00e-6 rad	4.31e-6 rad

## Conclusions

Modal estimates of noise parameters obtained by maximising the marginalised posterior distribution  $p(\phi|\mathbf{y})$ .

Applied to large scale coordinate metrology using laser trackers.

Calculations tractable using matrix factorisations, etc.

Posterior sampling algorithms: Markov chain Monte Carlo (Metropolis-Hastings with i) independent sampling, ii) random walks, iii) Hamiltonian (hybrid) Monte Carlo.

## Acknowledgements

Work supported by the EMRP JRP T3.J2.2 Metrology for New Industrial Measurement Technologies (PTB, NPL, INRIM, CMI, University of Maribor)

Support from MathMet 2010 gratefully acknowledged.

## Selected references

- A. B. Forbes. Surface fitting taking into account uncertainty structure in coordinate data. *Measurement Science and Technology*, 17:553–558, 2006.
- A. B. Forbes. Uncertainty evaluation associated with fitting geometric surfaces to coordinate data. *Metrologia*, 43(4):S282–S290, August 2006.
- A. B. Forbes. Nonlinear least squares and Bayesian inference. In F. Pavese, M. Bär, A. B. Forbes, J.-M. Linares, C. Perruchet, and N.-F. Zhang, editors, *Advanced Mathematical and Computational Tools in Metrology VIII*, pages 103–111, Singapore, 2009. World Scientific.
- A. B. Forbes. Parameter estimation based on least squares methods. In F. Pavese and A. B. Forbes, editors, *Data modeling for metrology and testing in measurement science*, pages 147–176, New York, 2009. Birkhäuser-Boston.
- A. B. Forbes and P. M. Harris. Uncertainty associated with co-ordinate measurements. In P. Shore, editor, *Laser Metrology and Machine Performance VII*, pages 30–39, Bedford, 2005. Euspen.
- A. B. Forbes, E. B. Hughes, and W. Sun. Comparison of measurements in coordinate metrology. *Measurement*, pages 1473–1477. 2009.
- A. B. Forbes and C. E. Matthews. Least squares, outliers and coordinate metrology. In K. Cheng and A. B. Forbes, editors, *Laser Metrology and Machine Performance IX*, pages 253–262, Bedford, 2009. Euspen.
- A. Gelman, J. B. Carlin, H. S. Stern and D B Rubin, *Bayesian Data Analysis*, Chapman&Hall/CRC, Boca Raton, 2004.
- G. N. Peggs, P. G. Maropoulos, E. B. Hughes, A. B. Forbes, S. Robson, M. Ziebart, and B. Muralikrishnan. Recent developments in large-scale dimensional metrology. *Journal of Engineering Manufacture: Part B*, 223:571–595, 2009.